

SIEMENS

NEW

SFH6941T

LOW CURRENT INPUT

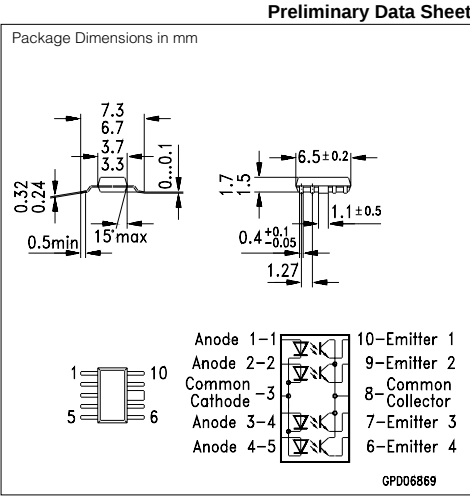
MINI OPTOCOUPLER

- FEATURES
- Transistor Optocoupler in SOT223 Package
 - End Stackable, 1.27 mm Spacing
 - Low Current Input
 - Very High CTR, 150% Typical at $I_F=1\text{ mA}$, $V_{CE}=0.5\text{ V}$
 - Good CTR Linearity Versus Forward Current
 - Minor CTR Degradation
 - Field Effect Stable by TRIOS® (Transparent IOn Shield)
 - High Collector-Emitter Voltage, $V_{CEO}=70\text{ V}$
 - Low Coupling Capacitance
 - High Common Mode Transient Immunity
 - Isolation Test Voltage: 2500 VDC
 - Available in Tape and Reel (suffix T)

- APPLICATIONS
- Telecommunication
 - SMT
 - PCMCIA
 - Instrumentation

DESCRIPTION

The SFH6941T is a four channel mini-optocoupler suitable for high density packaged PCB application. It has a minimum of 2500 VDC isolation from input to output. The device consists of four phototransistors as detectors. Each channel is individually controlled. The optocoupler is housed in a SOT223 package. All the cathodes of the input LEDs and all the collectors of the output transistors are commoned enabling a pin count reduction from 16 pins to 10 pins—a significant space savings as compared to four channels that are electrically isolated individually.



Absolute Maximum Ratings

Emitter (GaAlAs)	
Reverse Voltage.....	3 V
DC Forward Current.....	5 mA
Surge Forward Current ($t_p \leq 10\text{ }\mu\text{s}$).....	100 mA
Total Power Dissipation.....	10 mW
Detector (Si Phototransistor)	
Collector-Emitter Voltage.....	70 V
Emitter-Collector Voltage.....	7 V
Collector Current.....	10 mA
Surge Collector Current ($t_p \leq 1\text{ ms}$).....	20 mA
Total Power Dissipation.....	20 mW
Package Insulation	
Isolation Test Voltage	
(between emitter and detector, refer to climate DIN 40046, part 2, Nov. 74).....	
Creepage.....	2500 VDC
Clearance.....	$\geq 4\text{ mm}$
Comparative Tracking Index per DIN IEC 112/VDE0303, part 1.....	$\geq 4\text{ mm}$
Isolation Resistance	175
$V_{IO}=100\text{ V}$, $T_A=25^\circ\text{C}$	$\geq 10^{11}\text{ }\Omega$
$V_{IO}=100\text{ V}$, $T_A=100^\circ\text{C}$	$\geq 10^{10}\text{ }\Omega$
Storage Temperature Range.....	$-55\text{ to }+150^\circ\text{C}$
Ambient Temperature Range.....	$-55\text{ to }+100^\circ\text{C}$
Junction Temperature.....	100°C
Soldering Temperature ($t=10\text{ sec. max.}$).....	260°C
Dip soldering plus reflow soldering processes	

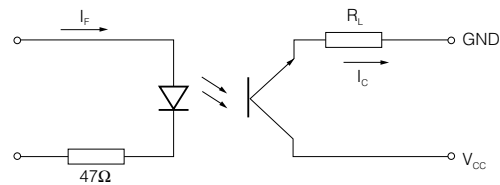
Specifications subject to change.

Characteristics ($T_A=25^{\circ}\text{C}$, unless otherwise specified)

Description	Symbol	Min.	Typ.	Max.	Unit
Emitter (IR GaAs)					
Forward Voltage, $I_F=5\text{ mA}$	V_F		1.25		V
Reverse Current, $V_R=3\text{ V}$	I_R		0.01	10	μA
Capacitance, $V_R=0\text{ V}$, $f=1\text{ MHz}$	C_0		5		pF
Thermal Resistance	R_{thJA}		1000		$^{\circ}\text{K/W}$
Detector (Si Phototransistor)					
Collector-Emitter Voltage, $I_{CE}=10\text{ }\mu\text{A}$	V_{CEO}	70			V
Emitter-Collector Voltage, $I_{EC}=10\text{ }\mu\text{A}$	V_{ECO}	7			V
Capacitance, $V_{CE}=5\text{ V}$, $f=1\text{ MHz}$	C_{CE}		6		pF
Thermal Resistance	R_{thJA}		500		$^{\circ}\text{K/W}$
Package					
Coupling Capacitance	C_C		1		pF

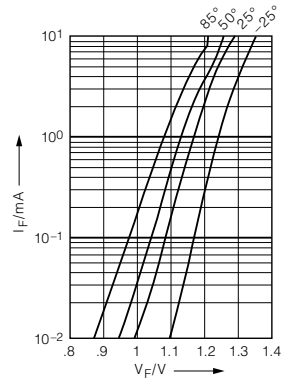
Description	Symbol	Values			Unit
		-3	-4	-5	
Coupling Transfer Ratio $I_F=1\text{ mA}$, $V_{CE}=0.5\text{ V}$ $I_F=0.5\text{ mA}$, $V_{CE}=1.5\text{ V}$	I_C/I_F I_C/I_F	100–200 120 (≥ 50)	160–320 200 (≥ 80)	250–500 300 (≥ 125)	%
Collector-Emitter Saturation Voltage $I_F=1\text{ mA}$	V_{CEsat}	0.25 (≤ 0.4) ($I_C=0.5\text{ mA}$)	0.25 (≤ 0.4) ($I_C=0.8\text{ mA}$)	0.25 (≤ 0.4) ($I_C=1.25\text{ mA}$)	V
Collector-Emitter Leakage Current $V_{CE}=10\text{ V}$	I_{CEO}	50	50	50	nA

Switching times, typical

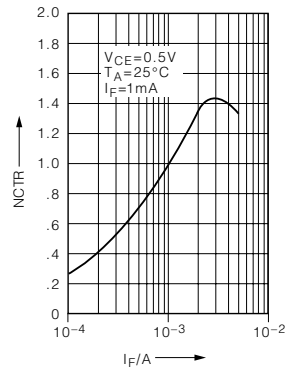


Description	Symbol	Values	Unit	Test Conditions
Turn-on Time	t_{on}	3	μs	$I_F=2\text{ mA}$ $R_L=100\text{ }\Omega$ $T_A=25^{\circ}\text{C}$ $V_{CC}=5\text{ V}$
Rise Time	t_r	2.6		
Turn-off Time	t_{off}	3.1		
Fall Time	t_f	2.8		

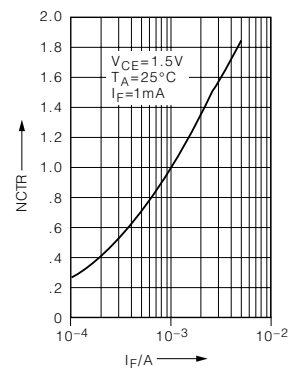
LED current versus LED voltage
 $V_F=f(I_F)$



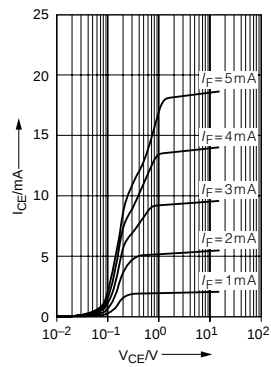
Saturated current transfer ratio
 normalized to $I_F=1$ mA, $NCTR=f(I_F)$



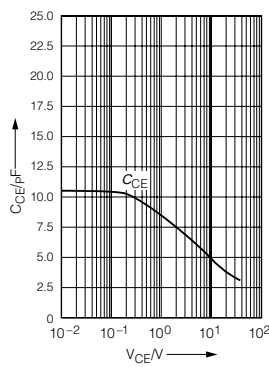
Non-saturated current transfer
 normalized to $I_F=1$ mA, $NCTR=f(I_F)$



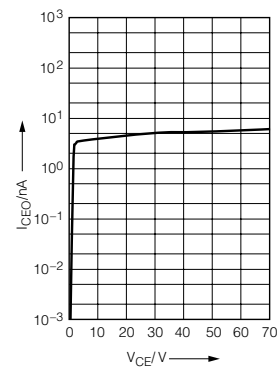
Transistor output characteristics
 $T_A=25^\circ\text{C}$, $I_{CE}=f(V_{CE}, I_F)$



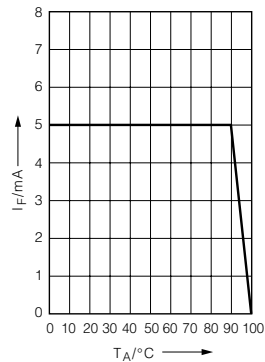
Transistor capacitance (typ.)
 $T_A=25^\circ\text{C}$, $f=1\text{MHz}$, $C_{CE}=f(V_{CE})$



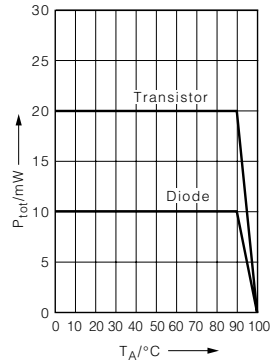
Collector-emitter leakage current (typ.)
 $I_F=0$, $T_A=25^\circ\text{C}$, $I_{CEO}=f(V_{CE})$



Permissible forward current diode
 $I_F=f(T_A=25^\circ\text{C})$



Permissible power dissipation
 $P_{tot}=f(T_A)$



$T_A=25^\circ\text{C}$, $I_F=1$ mA, $V_{CC}=5$ V,
 t_{on} , t_r , t_{off} , $t_f=f(R_L)$

